

IN THE SPECIFICATION

Please amend the specification as follows:

Please amend the first paragraph on page 1 after the title:

CROSS REFERENCE TO RELATED APPLICATIONS

This patent application is related to U.S. Patent Application Serial Number 10/789,895 entitled METHOD AND SYSTEM FOR AGGREGATING AND COMBINING MANUFACTURING DATA FOR ANALYSIS, to Naoki Toyoshima and Yuko Maeda, assigned to Micron Technology, Inc., ~~and incorporated herein by reference.~~

Please amend Table A on page 12, as follows:

Process	Time of Event	Sampled Value	Calculated Sampled Value assigned to Production Lot
Sample 1	tS_1	S_1	
Lot 1	tL_1		$L_1 = 1/(tS_2 - tS_1)\{S_1(tS_2 - tL_1) + S_2(tL_1 - tS_1)\}$
Lot 2	tL_2		
Lot _i	tL_i		$\bar{L}_i = 1/(tS_3 - tS_2)\{S_2(tS_3 - tL_2) + S_3(tL_2 - tS_2)\}$
Lot _{i+1}	tL_{i+1}		
Lot _{i+2}	tL_{i+2}		
Sample 2	tS_2	S_2	
Lot - j	tL_j	L_j	$L_j = 1/(tS_3 - tS_2)\{S_2(tS_3 - tL_j) + S_3(tL_j - tS_2)\}$
Lot - j+1			
Lot - j+2			
Lot - j+3			
Lot - j+4			
Lot - j+5			
Lot - j+6			
Sample 3	tS_3	S_3	
Lot - k	tL_k	L_k	$L_k = 1/(tS_4 - tS_3)\{S_3(tS_4 - tL_k) + S_4(tL_k - tS_3)\}$
Lot - k+1			
Lot - k+2			
Lot - k+3			
Lot - k+4			
Lot - k+5			
Sample 4	tS_4	S_4	
⋮	⋮	⋮	⋮